

Notice of References Cited	Application/Control No. 10/672,672	Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0051902	05-2002	Suenaga et al.	429/35
*	C	US-2003/0003342	01-2003	Sugita et al.	429/35
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	N	JP 2002-231272	08-2002	Japan	Wakahoi et al.	H01M 8/02
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NON-PATENT DOCUMENTS

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